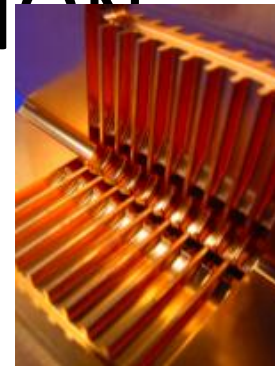




# LINEAR COLLIDER BEAM INSTRUMENTATION



T. LEFEVRE, CERN  
ON THE BEHALF OF THE LC BEAM INSTRUMENTATION  
COMMUNITY

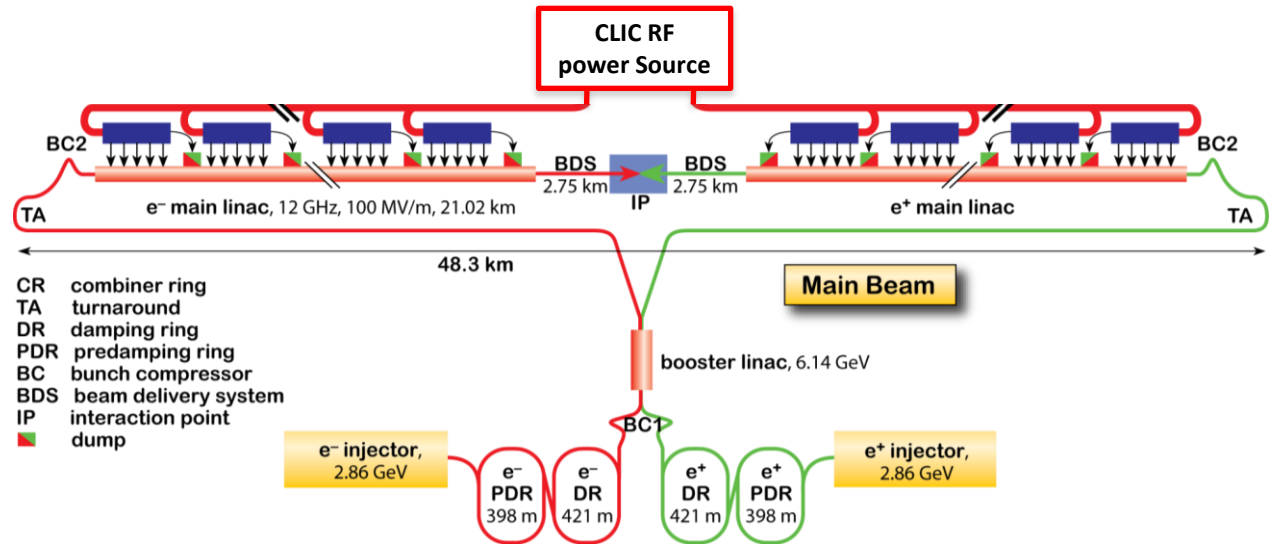
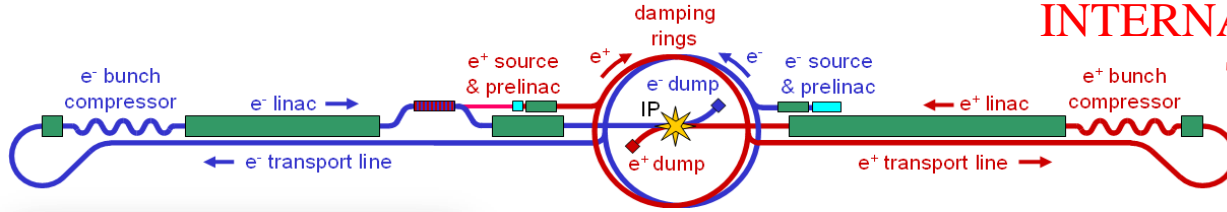


# LINEAR COLLIDER BEAM INSTRUMENTATION

- Overview of Beam Instrumentation for Linear Collider
- Selection (5) of the main beam instrumentation R&D
- Conclusion and perspectives

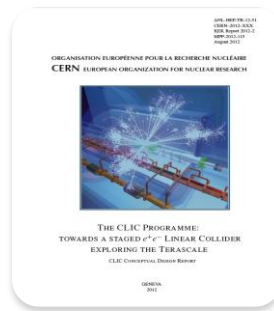
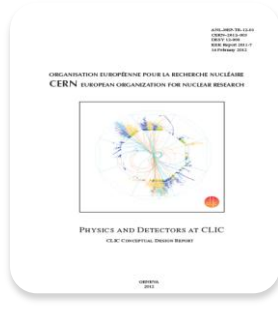
## INTERNATIONAL LINEAR COLLIDER Technical Design Report in 2013

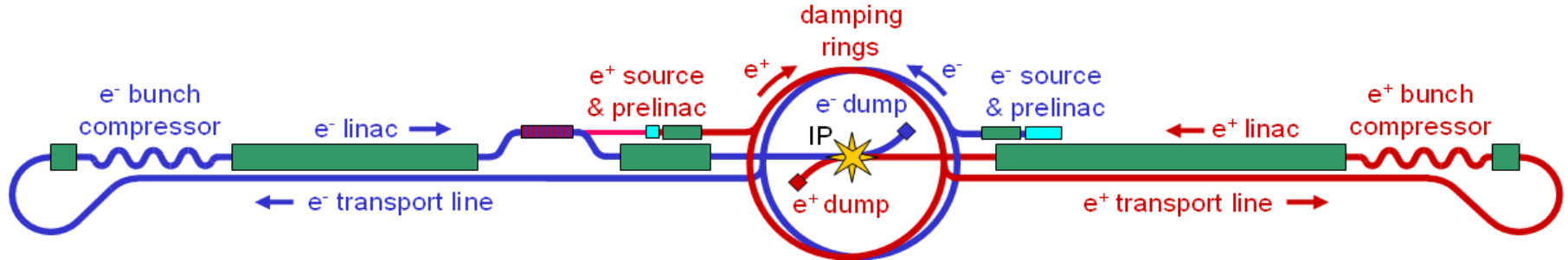
<http://www.linearcollider.org/>



<http://clc-study.org/>

## COMPACT LINEAR COLLIDER Conceptual Design Report in 2012

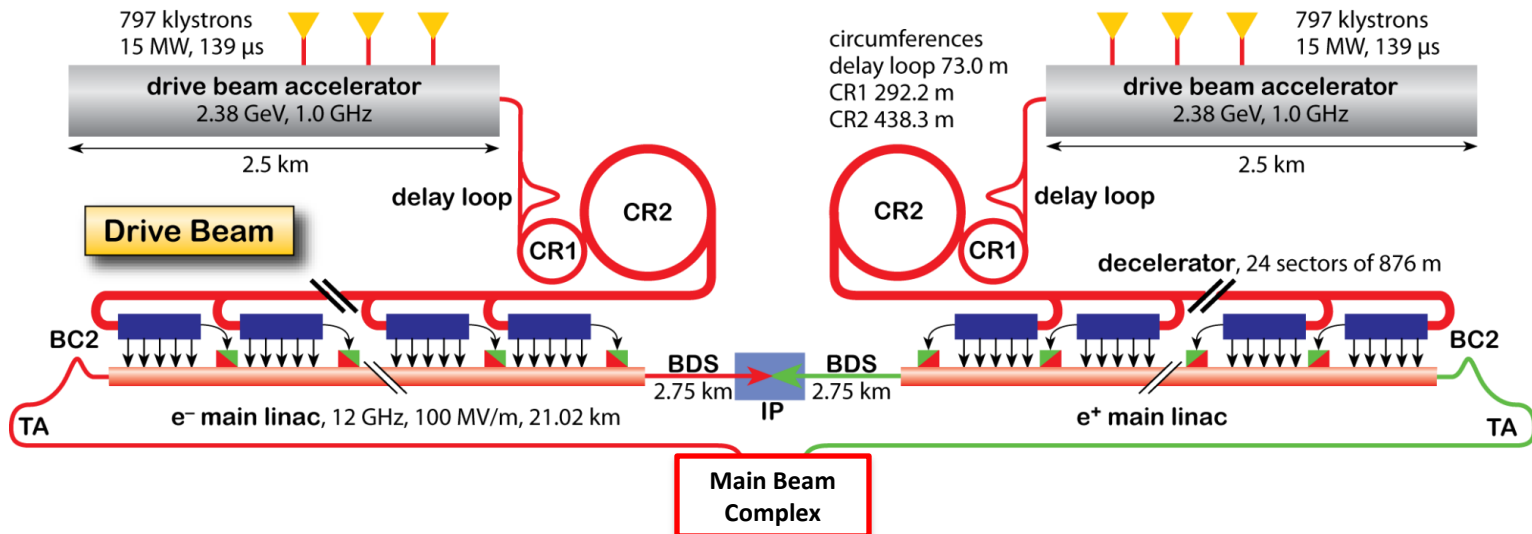




- As far as Beam Instrumentation is concerned, Colliding beams have **very similar issues and requirements for both projects** (*CLIC always little more demanding*)
- Collect requirements for the **whole accelerator complex**
  - Injector complex – Damping rings – long transfer lines – long main linacs – beam delivery system and dump lines (in CLIC ~ 100kms of beam line)
  - Most of the instruments in underground tunnel (in CLIC it accounts for 2/3 of the total)
  - In the tunnel, the number of instruments scales linearly with length (Energy) of the linac : 250/km
- Chosen **instruments and diagnostics** with corresponding technology choice
- Study **alternative solutions** which would impact either on cost or performance

- CLIC RF power source based on Drive Beams
- High intensity (100A) high frequency (12GHz) beams
- Accounts for another 100kms of beam lines and  $\sim 10^5$  beam instruments ( $>95\%$  in tunnel)
- Large number but more relaxed requirements

DB Instruments	Surface	Tunnel	Total
Intensity	38	240	278
Position	1834	44220	46054
Beam Size	32	768	800
Energy	18	192	210
Energy Spread	18	192	210
Bunch Length	24	288	312
Beam Loss	1730	44220	45950



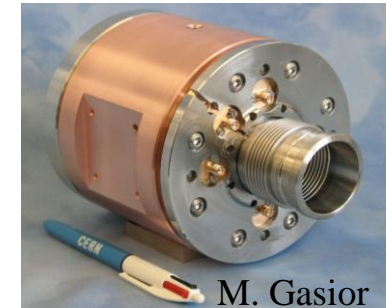
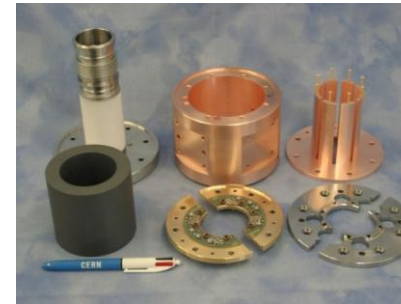
- Measuring small emittance and small beam size (non-intercepting devices)  
~ 1 $\mu$ m spatial resolution Transverse Profile Monitors
- Measuring short bunch length  
~ 20fs time resolution Longitudinal Profile Monitors
- Conservation of emittance over long distances relies on precise beam alignment  
high accuracy (5 $\mu$ m) high resolution (50nm) Beam Position Monitor
- Cost effective Beam position and Beam loss monitors for CLIC Drive beams



## Requirements:

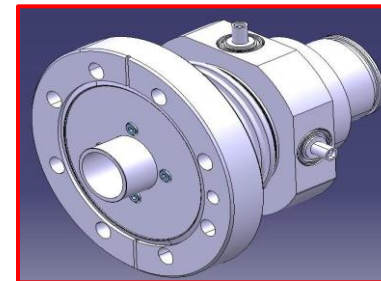
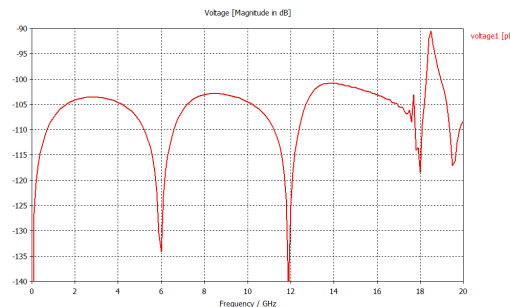
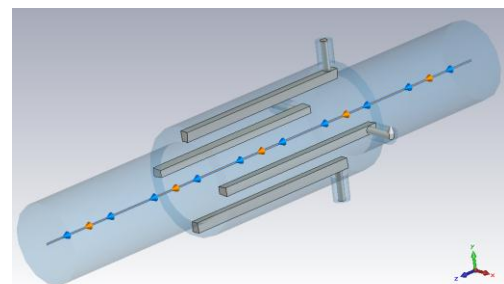
- High current 100A – high bunch frequency 12GHz
- In the vicinity of an RF structure producing 100MW @12GHz
- Temporal resolution of 10ns
- 2 micron resolution over an aperture of 23mm (accurate calibration)
- Simple and Cheap ~ 40k units

CLIC TEST FACILITY 3 uses Inductive Pick-ups  
~60 Units ~ 5um resolution measured



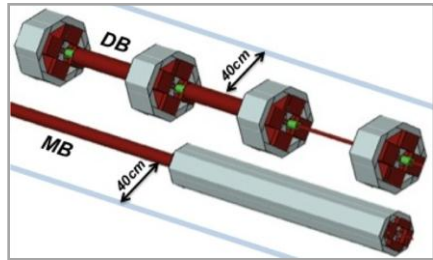
M. Gasior

Cheaper alternative based on Stripline Pick-ups (*A. Benot-Morell, S. Smith, M. Wendt, L. Soby*)



To be tested on CTF3 in 2013

FLUKA model to simulate secondary particle shower distributions requirements



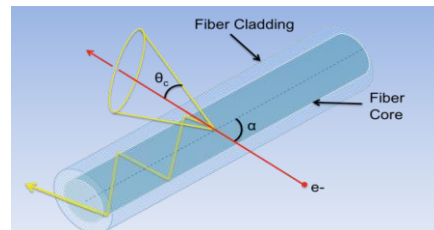
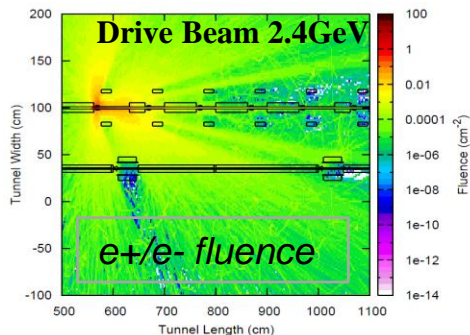
- Large dynamic  $10^5$  to cover destructive and operational losses
  - Annual dose  $\leq 50$  kGy at detector location
  - Ionization chambers as baseline choice : 1 detector/quadrupole
- Based on LHC ionization chamber and readout electronics with dynamic range  $10^5$  ( $10^6$  under investigation) and sensitivity  $7e10^{-9}$  Gy

Considering long distributed system based of optical fibers used as Cherenkov detectors



Fiber : 100m long, NA=0.22, 0.365mm  $\phi$

SiPM as photon detector



Analytical model

- $\approx 50\%$  more photons downstream
- Sensitivity requirements:  $\approx 10^4 - 10^5 N_{ph}/train$
- Dynamic range:  $\approx 10^4$
- Cherenkov model validated on beam tests (angular dependence)
- Loss longitudinal localization works for single bunch
- Quartz fibers tested ok up to 22 MGy
- Length cannot be longer than 100m (attenuation)



Nanometer BPM's using RF Cavities have been developed since the last 15 years (ATF2)

Output RF signal proportional to the beam offset

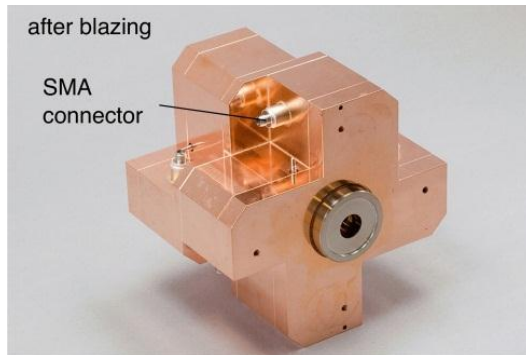
High precision mechanical machining of RF disks – brazing technique

## IP BPM system

(BPM + Ref) Cavity : **1 unit**

Target : 2 nm

Aperture: 6 mm



**Resolution 8.72 +-0.28(stat) +-0.35(sys) nm**  
 @  $0.7 \times 10^{10}$  electrons/bunch, @  $5\mu\text{m}$  dynamic range  
 Y. Inoue et al., Phys. Rev. ST-AB 11, 62801 (2008)

## C-band BPM system

BPM cavity: **units**

Reference cavity: **4 units**

Target resolution: 100 nm

Aperture: 20 mm

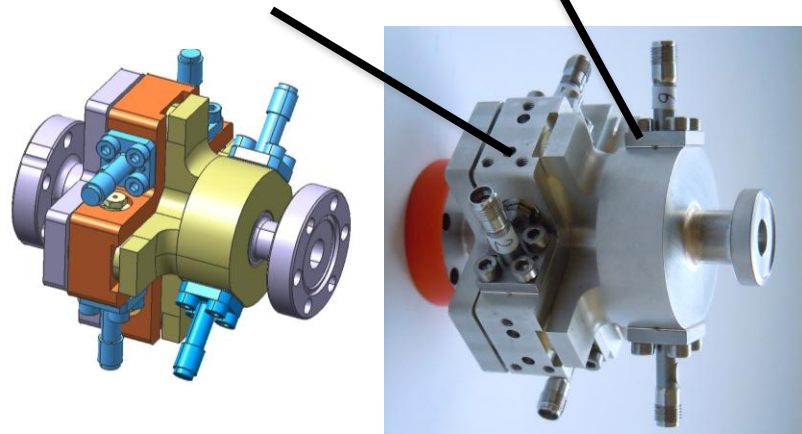


**Resolution 15.6 nm**  
 @dynamic range  $\pm 20\mu\text{m}$   
 S. Walston *et al*, NIM A578 1 (2007)

**Excellent resolution using low bandwidth cavity design !**

Dipole-mode  
“BPM” resonator  
& waveguide

Monopole-mode  
“REF” resonator



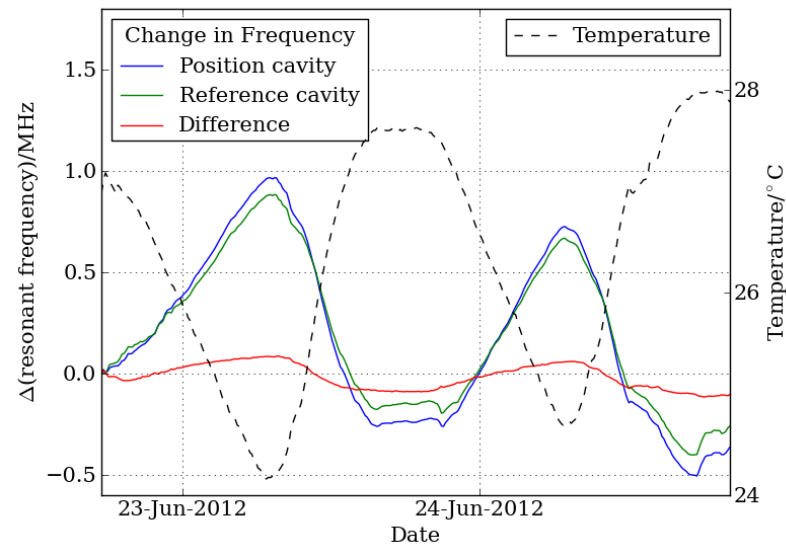
- Low quality factor to provide multiple position measurements within a single train
- RF characterization before and after brazing:

Cavity	Position	Reference
Resonant frequency/GHz	15.012	14.997
Loaded quality factor	198	150

Temperature stability of both cavities measured

Cavity	Temperature stability/kHz/°C
Position	-359
Reference	-308
Difference	51

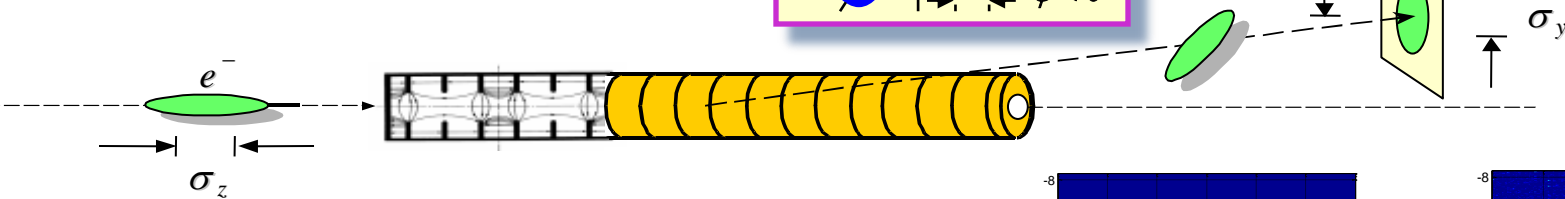
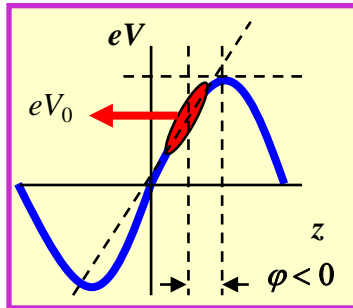
**Beam Tests foreseen in 2012/13 @ CTF3-TBTS**



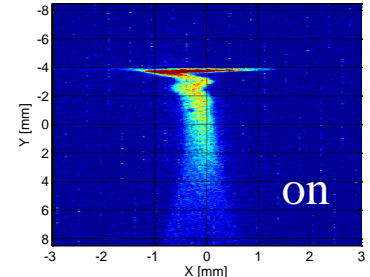
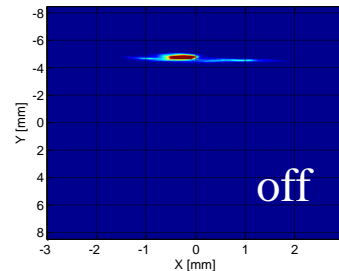
	ILC	CLIC linac	XFEL	LCLS
<i>Beam Energy (GeV)</i>	250	1500	20	15
<i>Linac RF Frequency (GHz)</i>	1.3	12	1.3	2.856
<i>Bunch charge (nC)</i>	3	0.6	1	1
<i>Bunch Length (fs)</i>	700	150	80	73

- High resolution and single shot longitudinal measurement:
  - Baseline solution using RF deflector : Excellent time resolution

- Old idea from the 60's
- RF Deflector ~ relativistic streak tube
- Used in almost all short bunch length facility



**!! But destructive method !!**

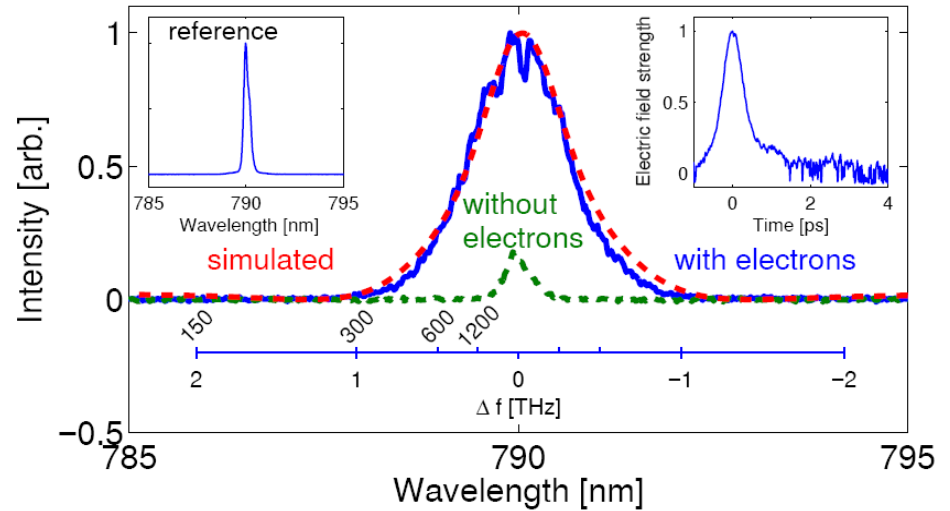
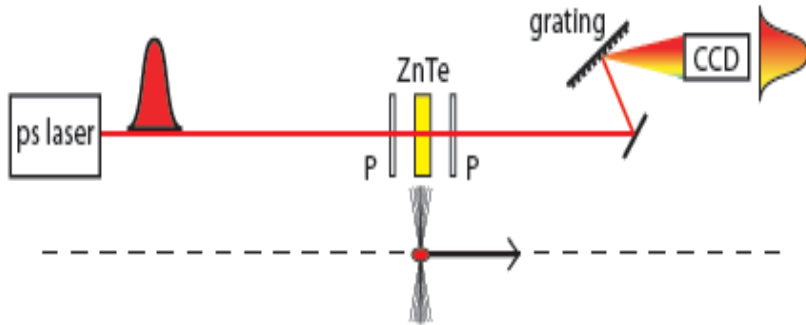


***Resolution of 4fs/pixels @ FLASH***

• **EO - Spectral Upconversion Techniques** - Convert the far-IR  $\rightarrow$  mid-IR spectrum to an optical spectrum

*Phys Rev Lett* **99**, 164801 (2007)  
*Phys. Rev. ST*, **12**, 032802 (2009)

- Bandwidth reduction [10 $\mu$ m – 1mm]  $\rightarrow$  [740-800]nm



• **Laser-generated THz pulses as mimic of electron bunch (Daresnury)**

• **Plan for beam tests at short test facility (PSI)**

• **EO Detection solution in advanced materials:** Very high bandwidth material (phonon resonances in far THz)

**Materials, Photonics & Smart Systems (MAPS) Group at Dundee**

Fabrication & Applications of Nanocomposites

- Required high precision from the Damping ring to the Interaction Point (IP)
  - Beam energy ranges from 2.4GeV  $\rightarrow$  1.5TeV
  - Tens of km of beam lines – Big number of instruments

• Flat Beams ( $\sigma_x \gg \sigma_y$ )

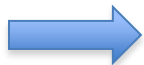
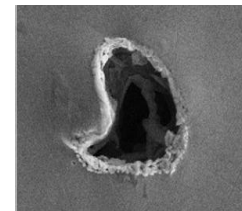
	ILC	CLIC	CLIC DB
Beam Charge (nC)	7875	190	$1.2 \cdot 10^6$
Hor. Emittance (nm.rad)	$10^4$	660	$10^8$
Ver. Emittance (nm.rad)	40	20	$10^8$

- Small beam size
- High beam charge



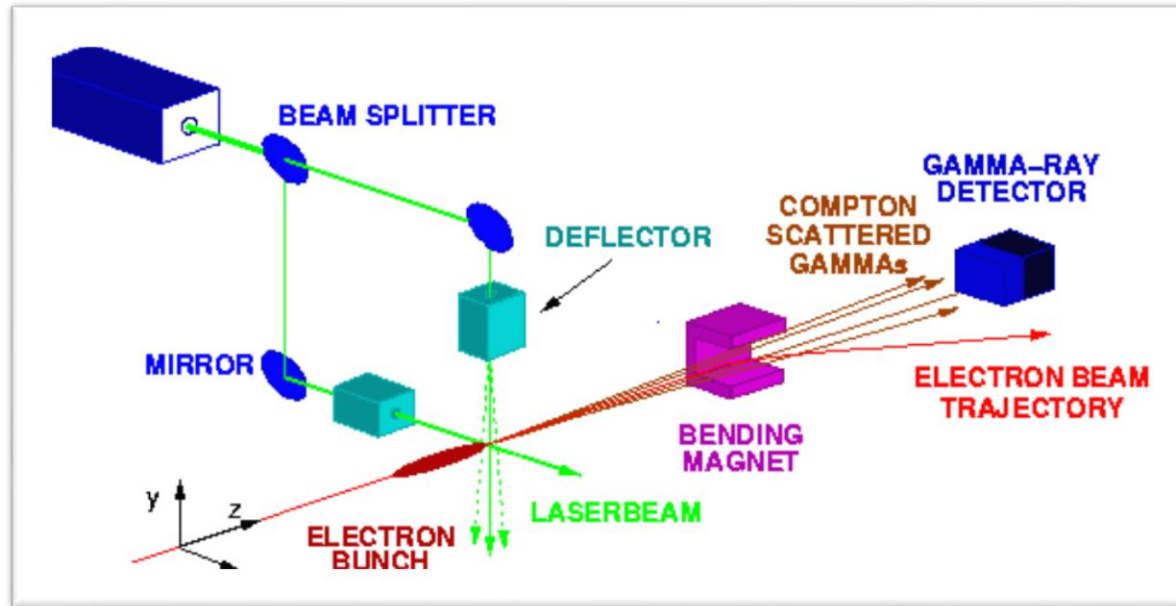
High Charge Densities  $> 10^{10}$  nC/cm<sup>2</sup>

Thermal limit for 'best' material (C, Be, SiC) is  $10^6$  nC/cm<sup>2</sup>



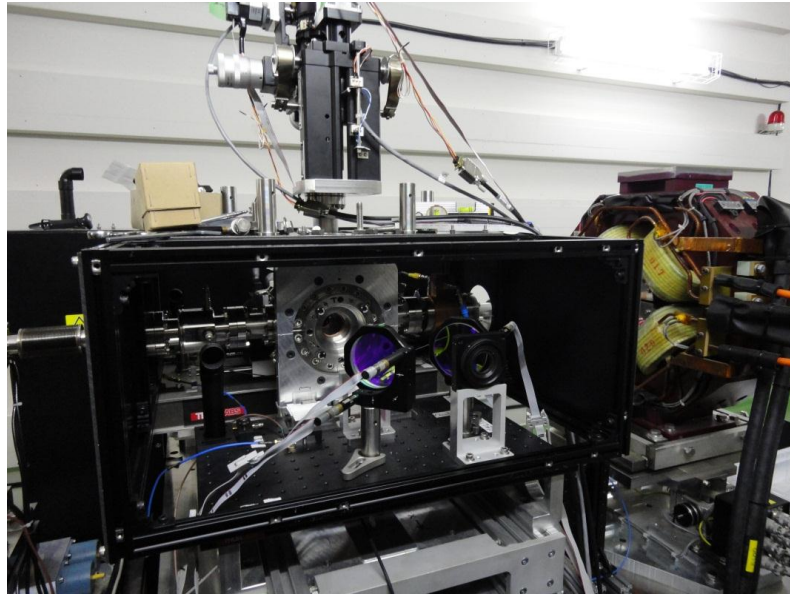
- Intercepting devices limited to single (or few) bunch
- Strong need for **non-intercepting devices**
- **Require two different systems** to cover the large beam intensity dynamic range (commissioning and production beams)

- High resolution non-interceptive transverse profile measurements using LWS
  - Goal to measure 1 $\mu$ m beam profile (resolution demonstrated on SLC in 90s)
  - Small Compton scattering cross section  $\rightarrow$  High power laser (10MW)



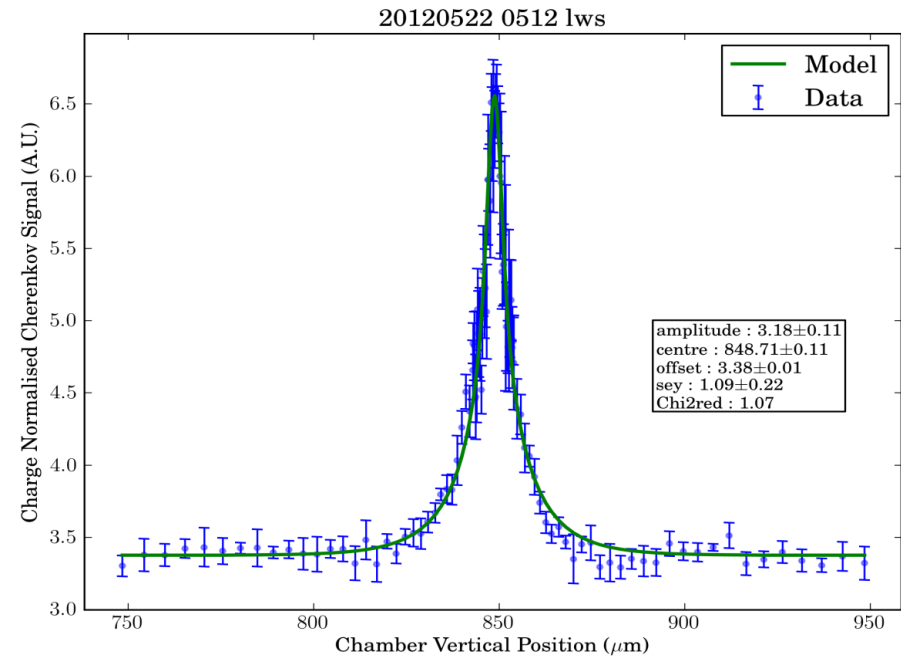
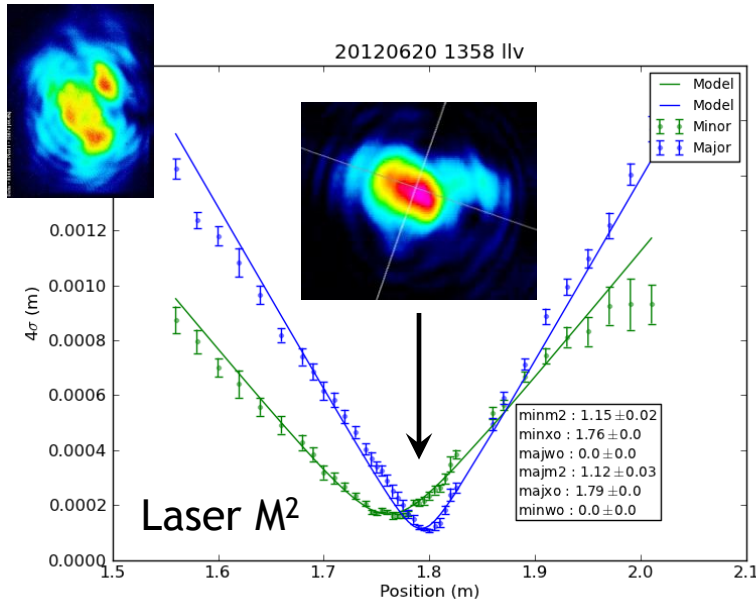
10 Years  
of R&D

- Spatial resolution requires strong laser focussing: (High quality fiber laser and optics, Diffraction limited spot size using large F#)
- Complexity and reliability: ‘Make it easy to operate’



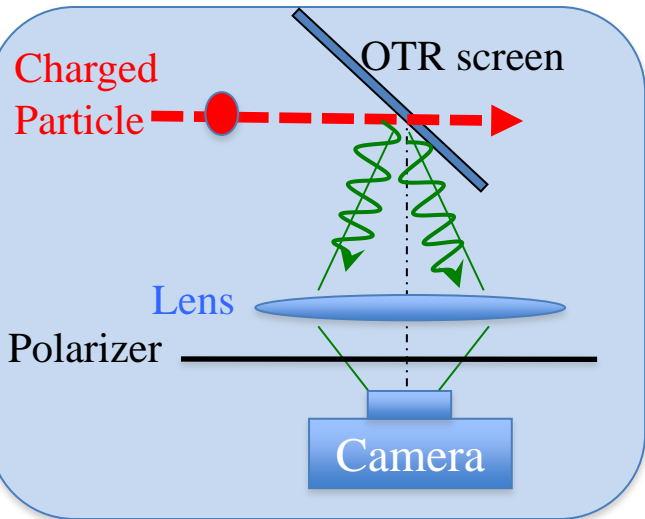
## ATF2 Laser-wire @ KEK in 2012

- LW moved during 2011 shutdown
- $e^-$  optics V:  $1\mu\text{m}$  x H:  $200\mu\text{m}$
- Lower background
- Laser focus characterised in depth
- **Further analysis on-going**



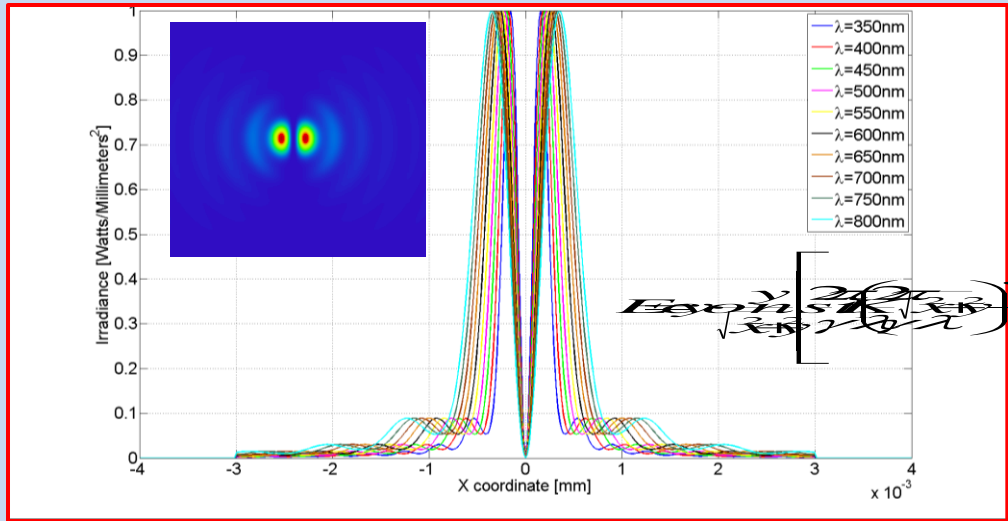
## Optical Transition Radiation

- Charged Particle passing through a dielectric material (high reflectivity)
- Interceptive method limited to single bunch
- Simple, reliable and cheap

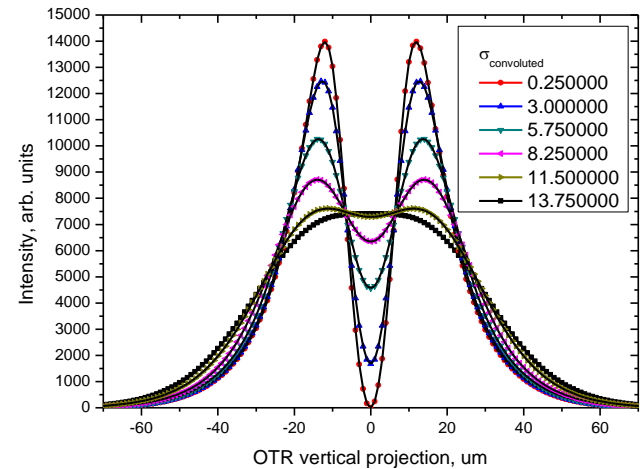


## Point spread function of OTR imaging system

~ Image generated by a single electron (Zemax simulations)

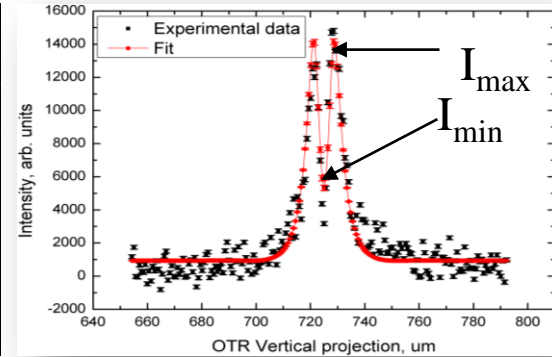
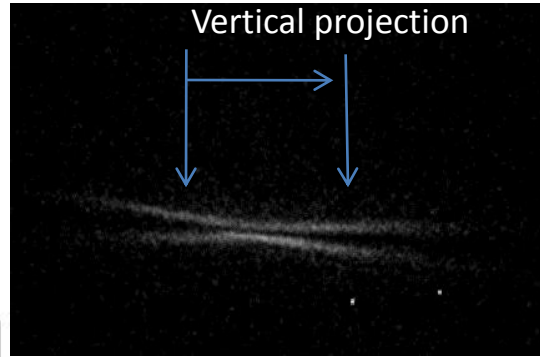
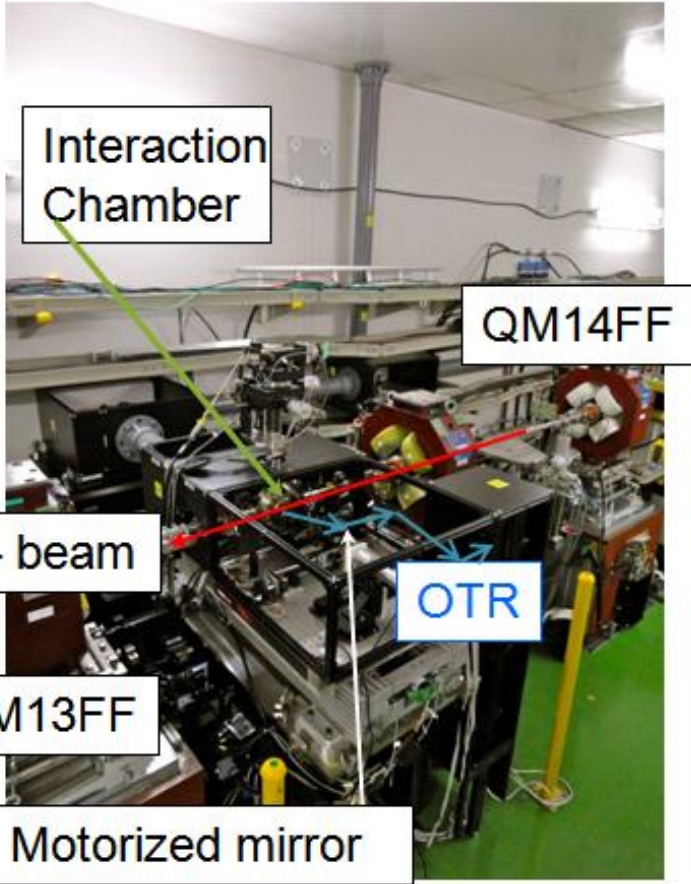


If we consider physical beam size, the resulting image on the camera is the convolution of the beam spatial distribution with the optical system PSF



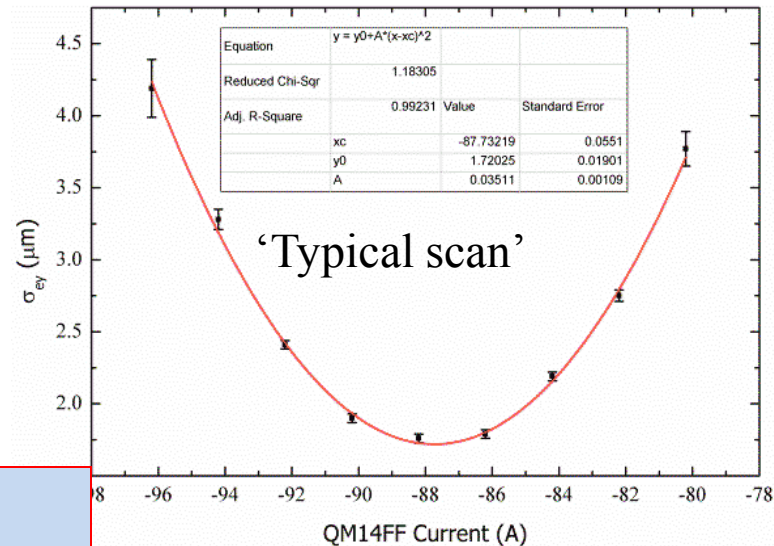


## ATF2 OTR PSF @ KEK in 2012



$$f(x) = a + \frac{b}{1 + [c(x - \Delta x)]^4} [1 - e^{-2c^2\sigma^2} \cos[c(x - \Delta x)]]$$

**a** 522.981 +/- 4.43887  
**b** 37773.1 +/- 116.182  
**c** 0.231221 +/- 0.00049  
 $\Delta x$  786.905 +/- 0.00679  
 $\sigma$  calibrated 1.28202 +/- 0.0479

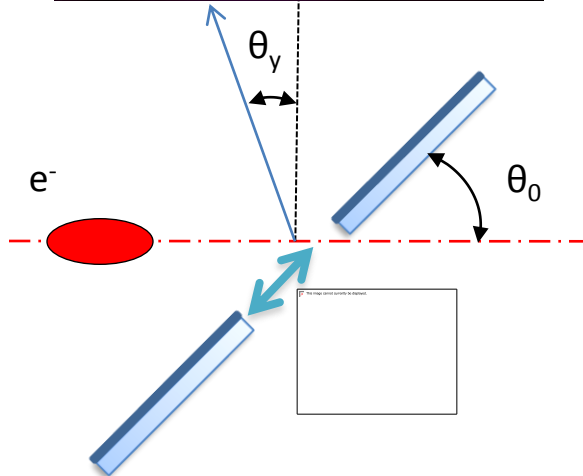
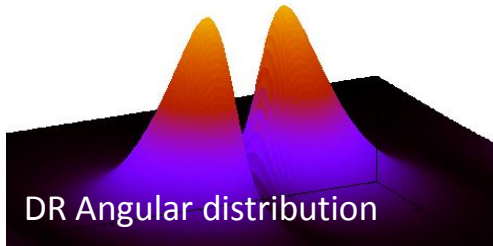


*P. Karataev et.al, Phys. Rev. Letters* **107**, 174801 (2011)  
*A. Arshiev, et.al, Journal of Physics: Conference Series* **236** (2010) 012008

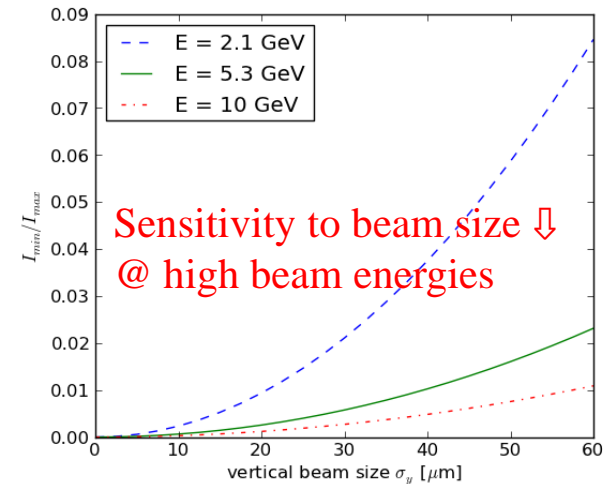
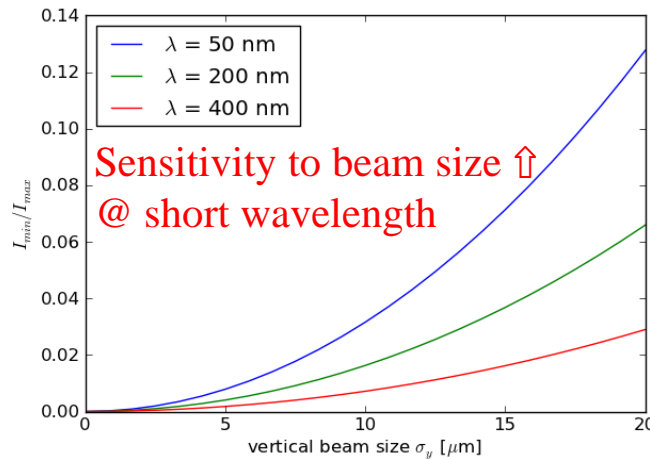
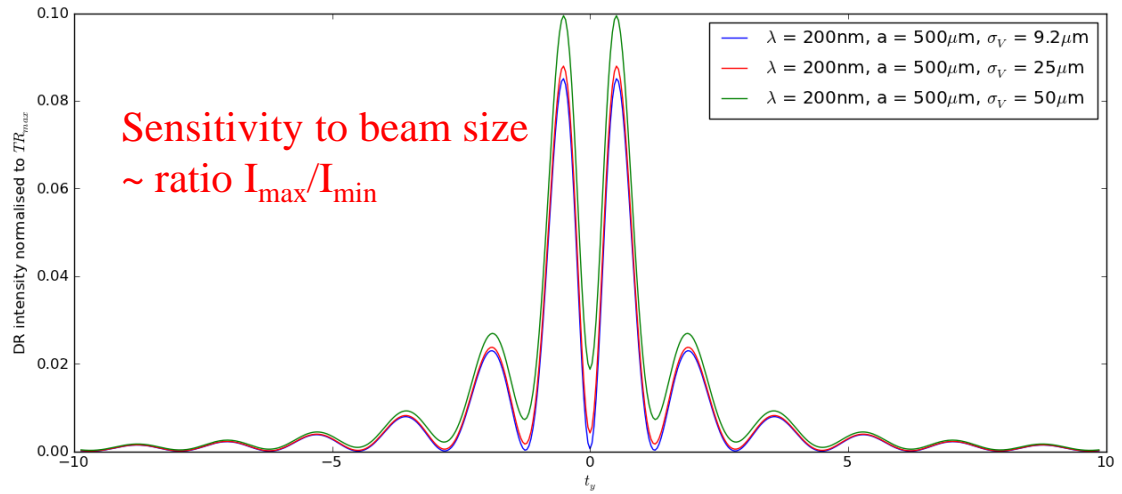
- Improving image quality (aberration, field of depth,..)
- Propose to test similar system close to final focus

## Diffraction Radiation

- Interference pattern between the diffraction radiation emitted by the edges of the slit
- Vertical beam size in DR vertical polarization



DR intensity  $\uparrow$  as slit size  $\downarrow$



A. Cianchi et al., *Phys. Rev. ST Accel. Beams* 14 (10) 102803 (2011)  
 A.H. Lumpkin et al., *Phys. Rev. ST Accel. Beams* 10, 022802 (2007)

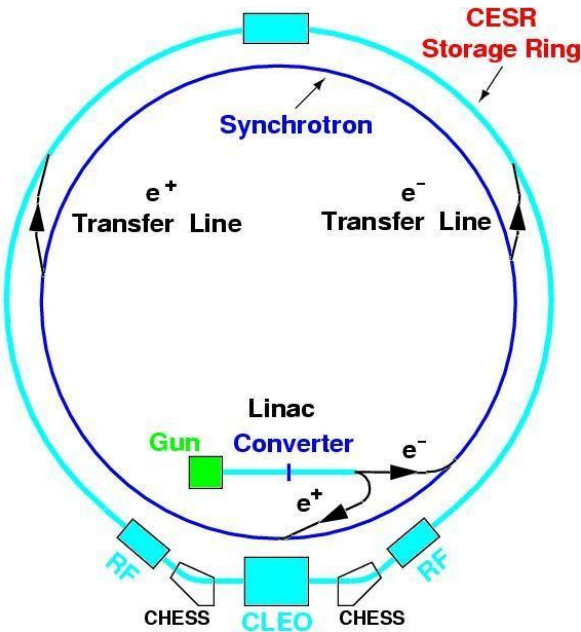
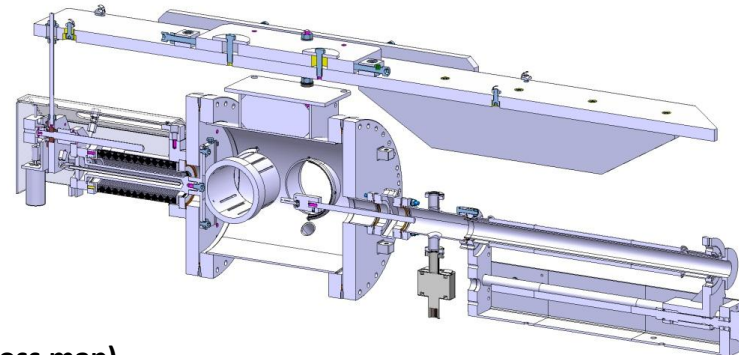
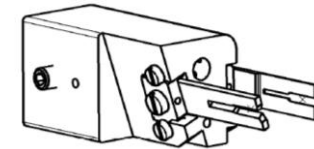
P. Karataev et al., *Phys. Rev. Lett.* 93, 244802 (2004)  
 L. Bobb, T. Aumeyr, M. Billing, D. Rubin, N. Chritin, P. Karataev, T. Lefevre

## Test foreseen on Cornell Electron Storage Ring in 2012/13

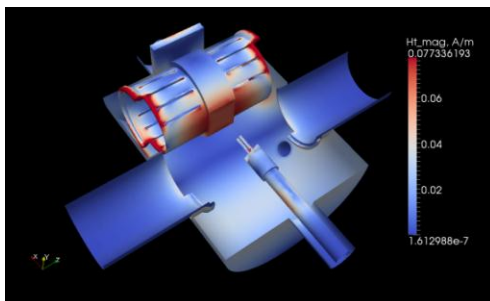
### Target Assembly

- Mask to suppress background from Synchrotron radiation
- Target for Diffraction Radiation:  $\lambda/100$  roughness,  $\lambda/10$  coplanarity

E (GeV)	$\sigma_H$ ( $\mu\text{m}$ )	$\sigma_V$ ( $\mu\text{m}$ )
2.1	320	$\sim 9.2$
5.3	2500	$\sim 65$



H-field surface tang complex magnitude (Loss map)  
 Mode Fr = 1.19 GHz, Q = 3309, Ploss = 0.075 W



Total power loss for single bunch = 0.6 W

- Phase 1 working at 400 and/or 200nm : beam size measurement  $\sim 30\text{-}50\mu\text{m}$
- Phase 2 program to use shorter wavelength ( $< 50\text{nm}$ )

- LC Beam Instrumentation is a very active field relying on large collaboration
- No feasibility issues but still many technical challenges in wide range of disciplines  
*Electronics, RF, Sensors, Radiation hardness, Laser and Optics, High precision machining and polishing, ...*
- Baseline choices have been made but R&D is going on in many areas
  - Reliability, Simplicity and Cost optimization driving the R&D efforts  
(not always compatible with tight tolerances as required)
- Large amount of devices to built and operate (*beyond what was already achieved in our field*),
  - Realistic Integration of instruments in the Machine layout to be finalized
  - Standardization is a key concept for operation and maintenance

Institute of Electrical and Electronics Engineers

**2012 IEEE NSS/MIC/RTSD Anaheim, California**

27 October - 3 November 2012



Thanks all the ILC/CLIC contributors to the talk

Thanks for your attention